

Describing the optical properties of astronomical dust analogs through numerical techniques

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Outline

- 1 Introduction
 - The interstellar medium in the infrared
 - The quest for the optical constants
- 2 Modeling
 - Previous work
 - Methodology
- 3 Results
 - Experimental data and apparatus
 - Analytical outputs
- 4 Summary
 - Conclusions
 - Future perspectives

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The relation between dust and the infrared

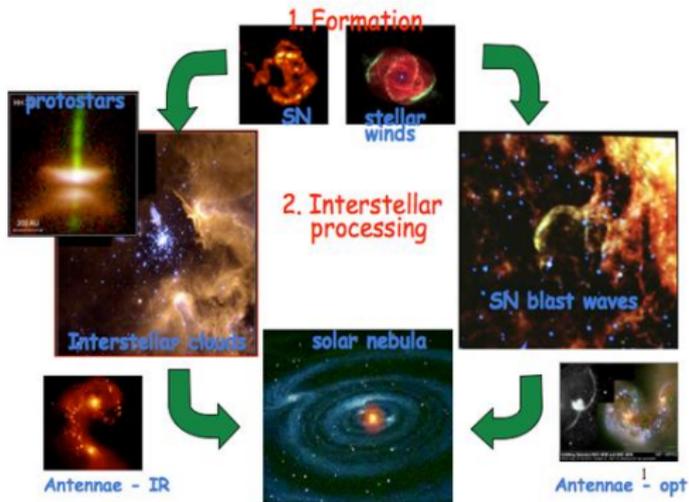


Figure: Formation, processing, and evolution of interstellar dust (Rinehart et al., 2008)

Interstellar dust:

- plays a role in the birth of **stars**
- precursor material for the formation of **planets**
- hides astronomical objects from our view

Infrared observations are crucial to understanding the origins of the universe.

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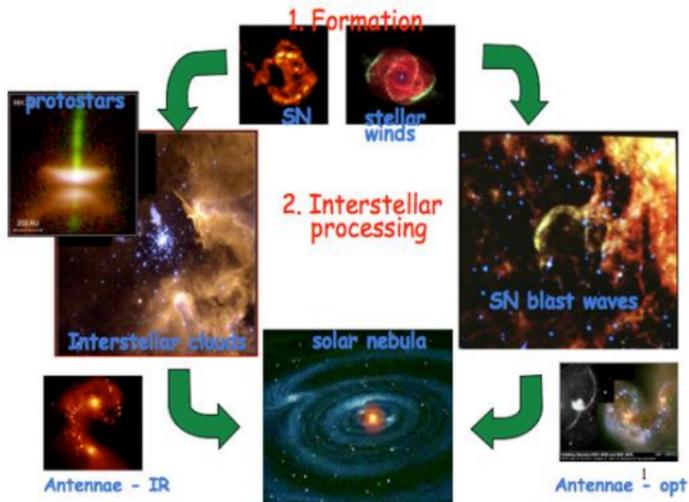


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The importance of studying silicates

Spectral features attributed to:

- silicates
- carbonaceous grains
- PAHs

Constraints on chemical and physical structure

Their spectra need be analyzed through laboratory experiments reproducing astrophysical environments. (See Henning & Mutschke, 2010)

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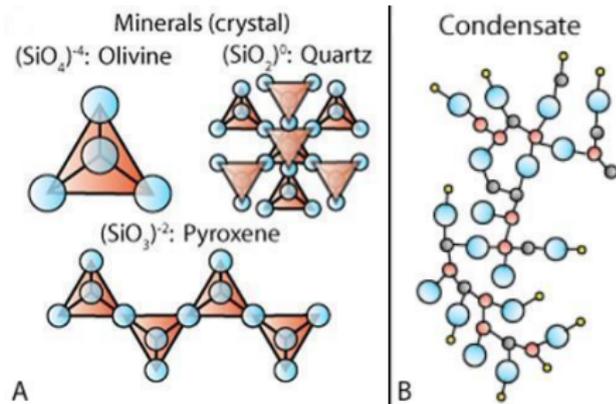


Figure: A) Silicates on Earth are ordered solids. B) In space their structure is chaotic. (Adapted from Rinehart et al., 2008)

The optical constants as primary parameters

Definition

Complex refractive index $m = n + ik$

- The **refractive index** n determines the velocity of constant-phase waves.
- The **extinction index** k determines the attenuation of the wave as it propagates through the medium.

Definition

Dielectric constant $\varepsilon = (n + ik)^2 = \varepsilon' + i\varepsilon''$

Problem: the optical constants are not directly measurable.

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- Experimental apparatus and measurements
- Development of **numerical algorithms** for the computation of the optical constants as a function of wavelength and temperature
- Validation through application to **laboratory data**
- Analysis and interpretation of post-processed data
- Population of a **library** of optical properties in the far-infrared regime

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Hypotheses and mathematical models

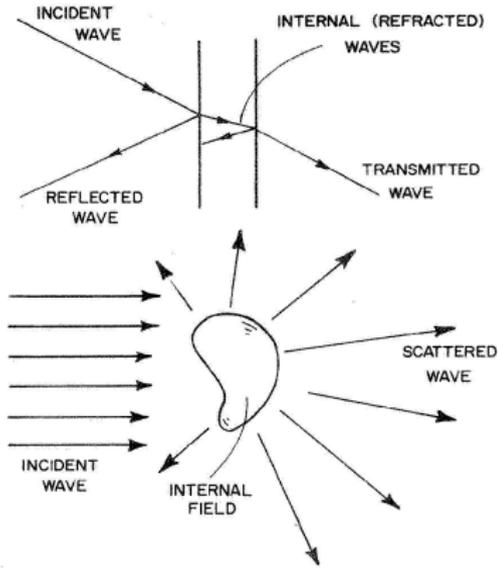


Figure: Analogy between scattering by a particle and transmission-reflection-absorption by a slab (Bohren and Huffman, 1983)

Transmission-line approximation

- One-layer slab model (Bohren and Huffman, 1983)
- Beer's law (Halpern et al., 1986)

Transition modes

- Lorentz model

Mixtures

- Maxwell-Garnett formula (Maxwell Garnett, 1904)

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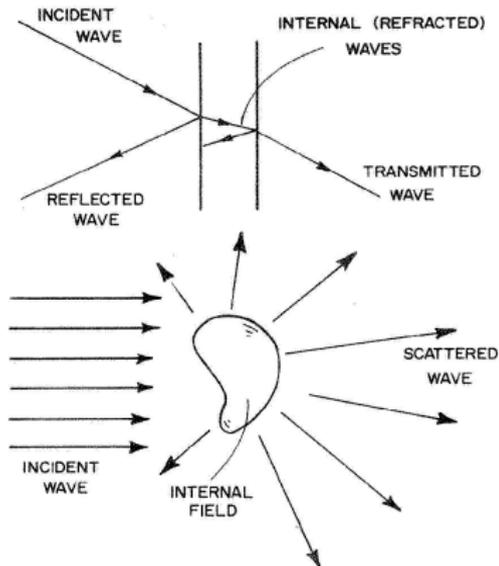


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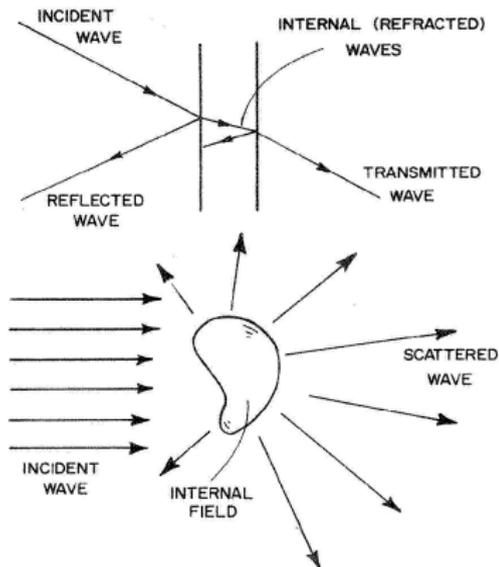


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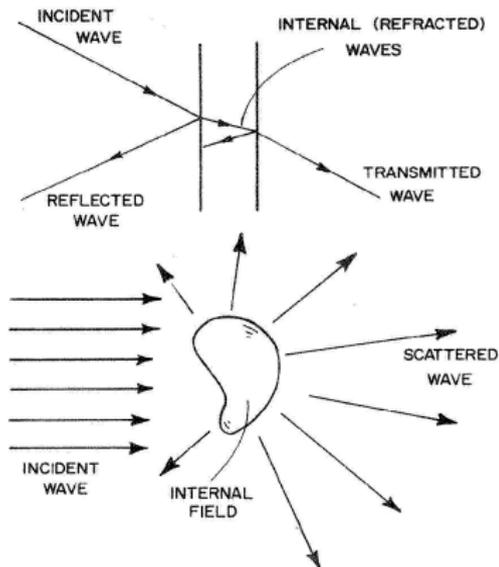


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Constrained minimization as main working tool

Definition (Least-Squares Nonlinear Fit)

$$\min_{DOFs} \chi_m^2 = \min_{DOFs} \frac{1}{N} \sum_{j=1}^N [T(DOFs, \lambda_j) - T_{measured}]^2$$

$$DOF_{min} \leq DOF \leq DOF_{max}$$

N = number of data points

λ = wavelength

Initial condition \rightarrow Fit \rightarrow $DOFs \rightarrow \left\{ \begin{array}{l} T, R, A \\ n, k, \epsilon \end{array} \right. \forall \lambda_j$

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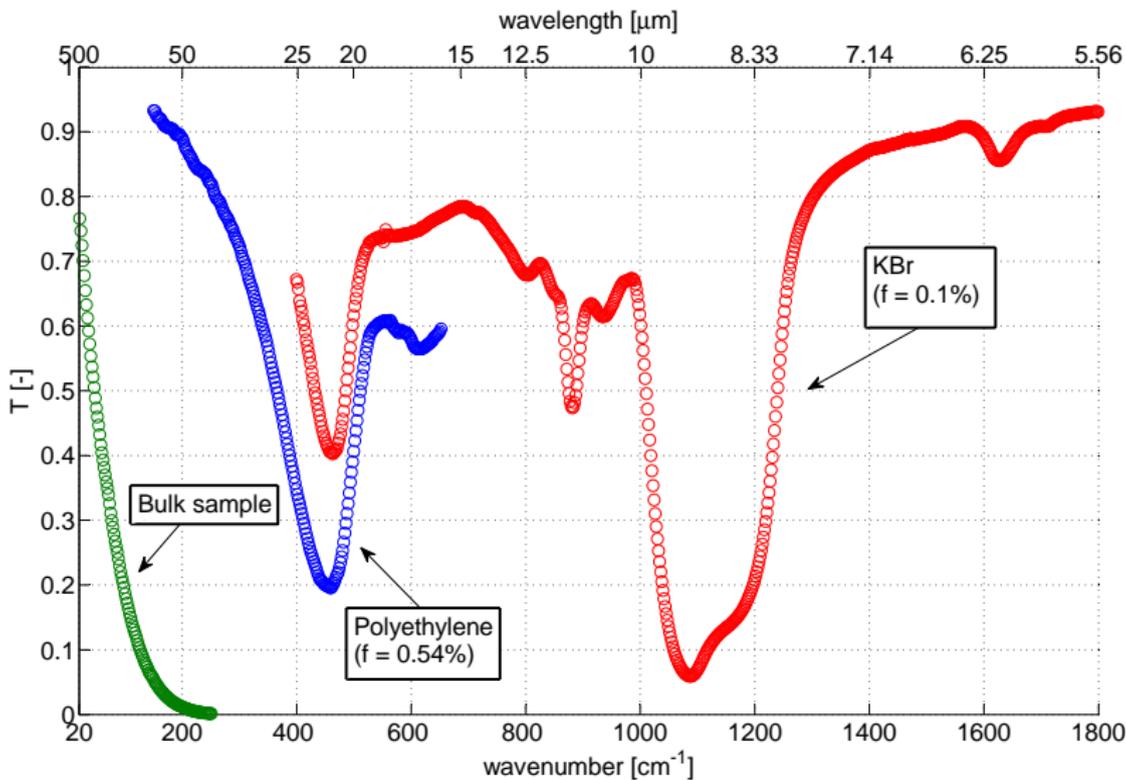
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SiO_x : Measured transmission spectrum at room temperature



SiO_x : Sample characterization



Figure: Various sample preparations are needed to cover the wide frequency range (Rinehart, Cataldo, et al., *Applied Optics*, in press).

SiO_x : Sample characterization

Each sample preparation has a **different optical depth**, which allows us to obtain transmission values in the range of 0.2-0.8 as needed to determine the optical constants to high accuracy.

| Sample type | Spectral coverage [μm] |
|--------------|-------------------------------------|
| 8-mm | 300 – 1000 |
| 4-mm | 100 – 500 |
| 2-mm | 100 – 350 |
| Polyethylene | 15 – 100 |
| KBr | 1 – 25 |

SiO_x : How to extract the optical constants (bulk samples)

Beer's law

$$T = (1 - R)^2 \exp(-\alpha h)$$

$$R = \frac{(n - 1)^2 + k^2}{(n + 1)^2 + k^2}$$

$$\alpha = a \left(\frac{\omega}{2\pi} \right)^b$$

h = sample thickness

$$k = \frac{\alpha}{2\omega} = \frac{a}{2\omega} \left(\frac{\omega}{2\pi} \right)^{b-1}$$

$$T = T(n, a, b)$$

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SiO_x : How to extract the optical constants (mixtures)

Maxwell-Garnett formula

$$\varepsilon_{eff} = \varepsilon_{eff}(f, \varepsilon_b, \varepsilon_i) \quad \text{▶}$$

Lorentz model

$$\varepsilon_i = (n + ik)^2 = \varepsilon_{i,\infty} + \sum_{j=1}^M b_m \frac{\omega_{p,j}^2}{\omega_{0,j}^2 - \omega^2 - i\omega\nu_j} = \varepsilon_i(DOFS_i, \omega)$$

Modified Lorentz model (Sihvola, 1999)

$$\varepsilon_{eff} = \varepsilon_{eff}(f, \varepsilon_b, DOFS_i, \omega)$$

One-layer slab model (averaged)

$$T = T[f, \varepsilon_b, (4M + 1)DOFS_i, \omega]$$

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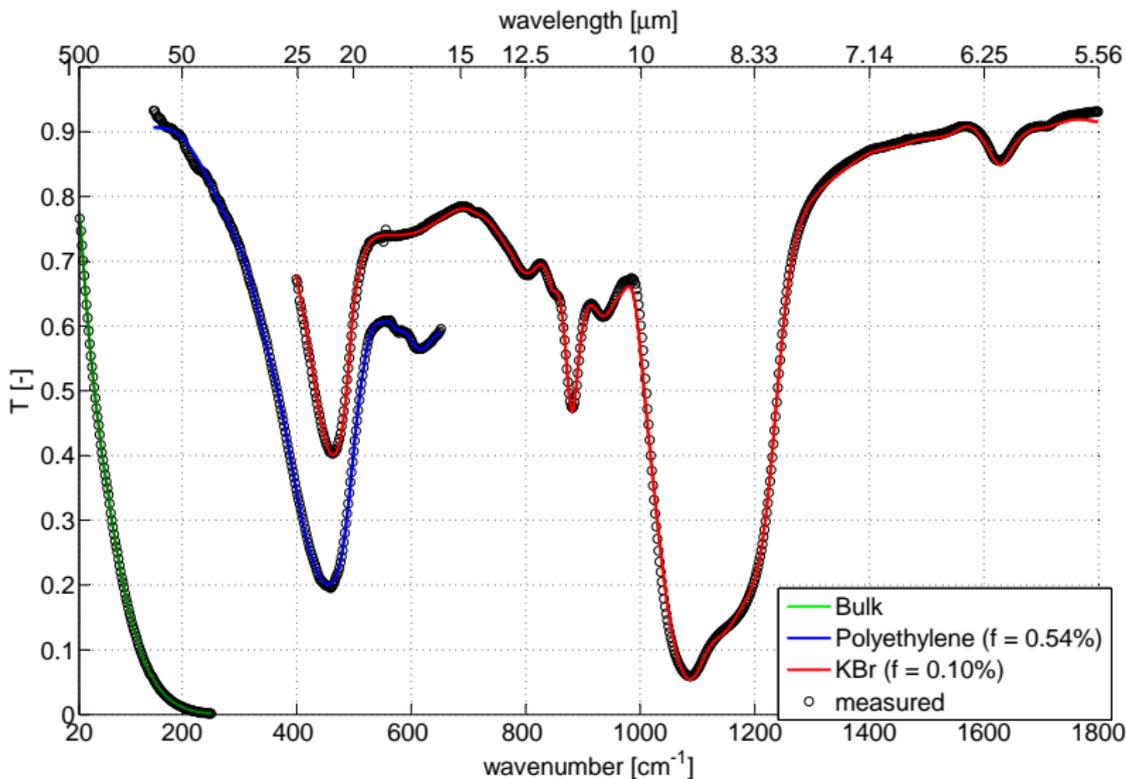
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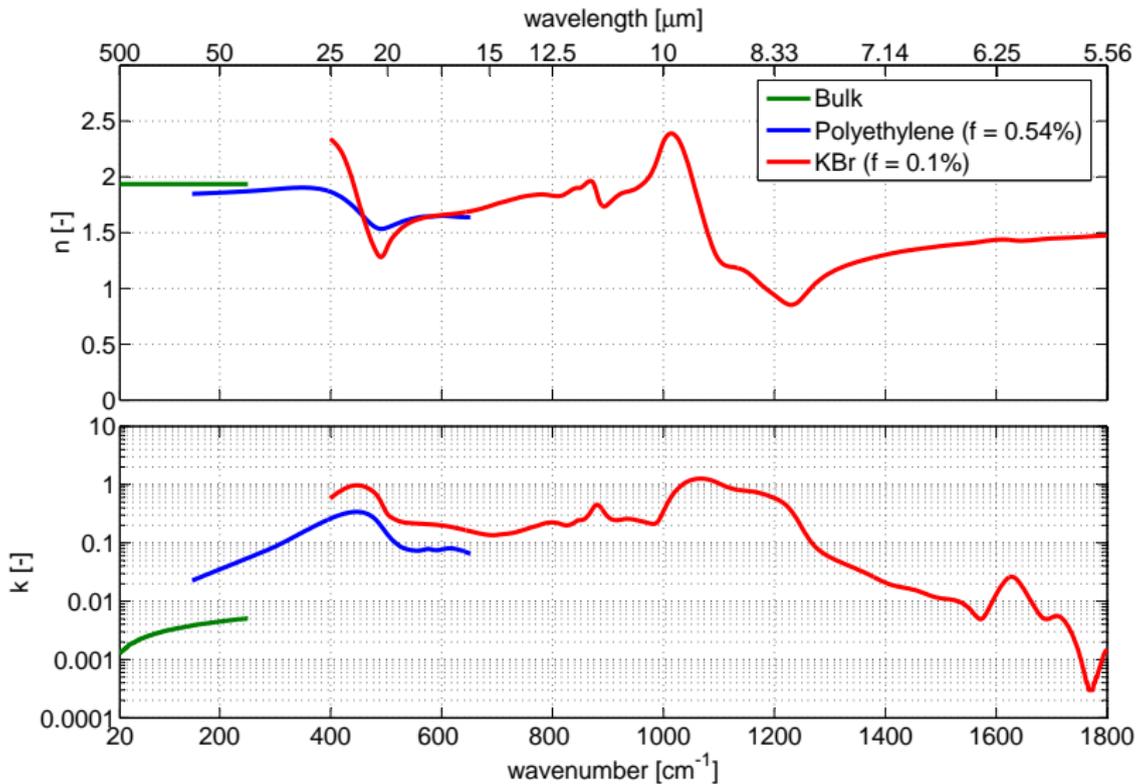
SiO_x : Fit and output parameters (Cataldo et al., in prep.)



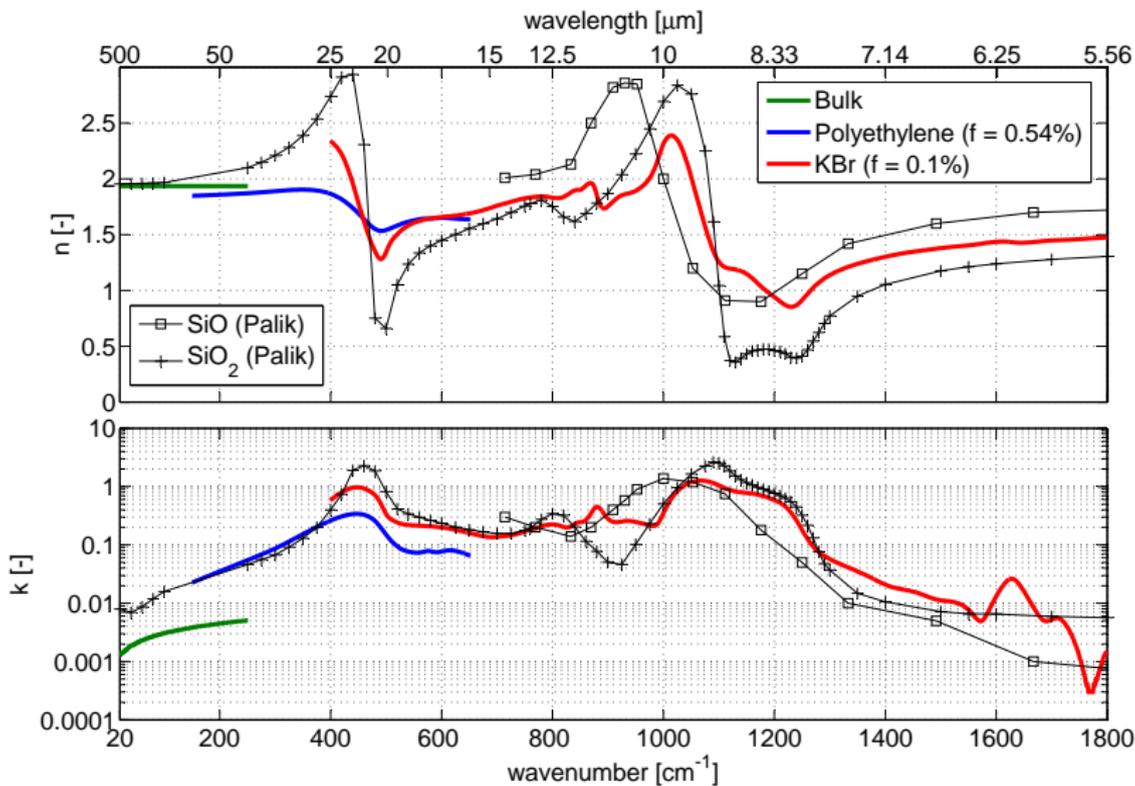
SiO_x : Fit and output parameters

| | | Bulk (4-mm) | Polyethylene | KBr |
|--------------|---------|----------------------|-----------------------|----------------------|
| DOFs | | 3 | 53 (13 LOs) | 153 (38 LOs) |
| Residual | average | 0.32 | 0.62 | 0.25 |
| | maximum | 2.68 | 3.93 | 1.47 |
| χ_m^2 | | $2.55 \cdot 10^{-5}$ | $11.12 \cdot 10^{-5}$ | $1.29 \cdot 10^{-5}$ |
| σ | | 0.005 | 0.012 | 0.008 |
| χ^2 | | 109.89 | 239.81 | 146.26 |
| χ_ν^2 | | 0.93 | 1.15 | 0.25 |

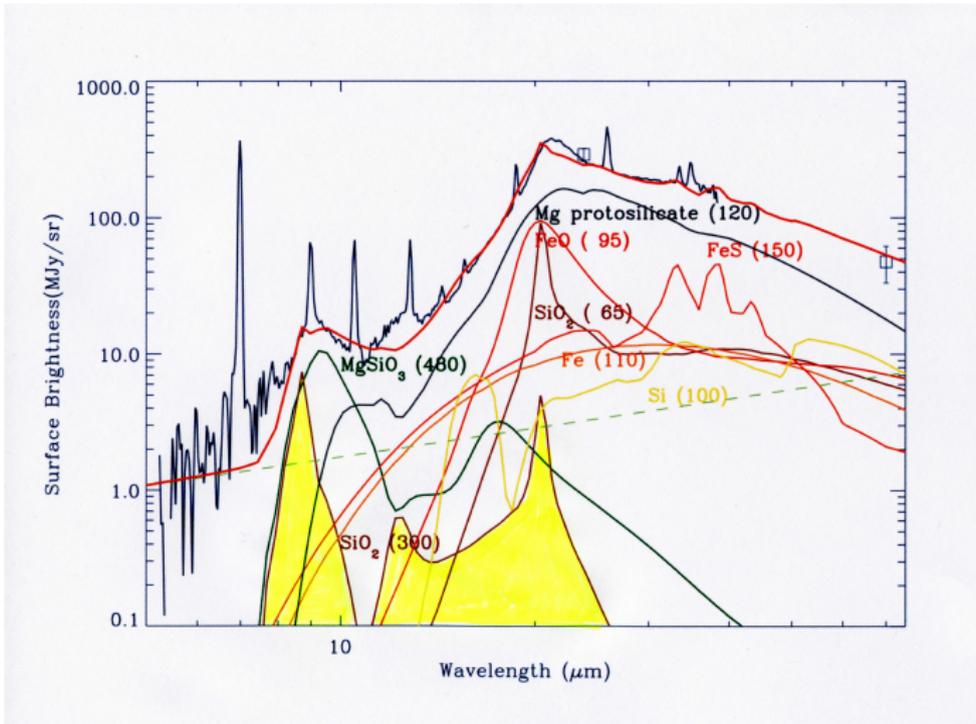
SiO_x : The optical constants in the FIR and MIR



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(Adapted from Rho et al., 2008)

Our sample description

| | Advantages | Disadvantages |
|-------------|---|-------------------------------------|
| Bulk sample | n consistent with other measurements | n not well constrained |
| | $a = 0.003$, $b = 1.552$ (Agladze et al., 95;...) | Need for data at longer wavelengths |
| Mixture | $n - k$ independent from filling fraction  | $n - k$ dependent on matrix |
| | $x \approx 1.5$ | Fine-tuning |
| | DOFs well constrained | of starting guess |
| | Outputs for mix and particles  | Uncertainty in measurements |

Next steps

- Measured **reflectance** data (TOP PRIORITY)
- **Temperature** dependence (Cataldo et al., in prep.)
- Development of more sophisticated models
 - **Metal-enriched** powders: Fe- and Mg-rich silicates (Kinzer, Cataldo, et al., in prep.)
 - **Scattering**
 - Multiple-layered structures
 - Unparalleled faces and roughness
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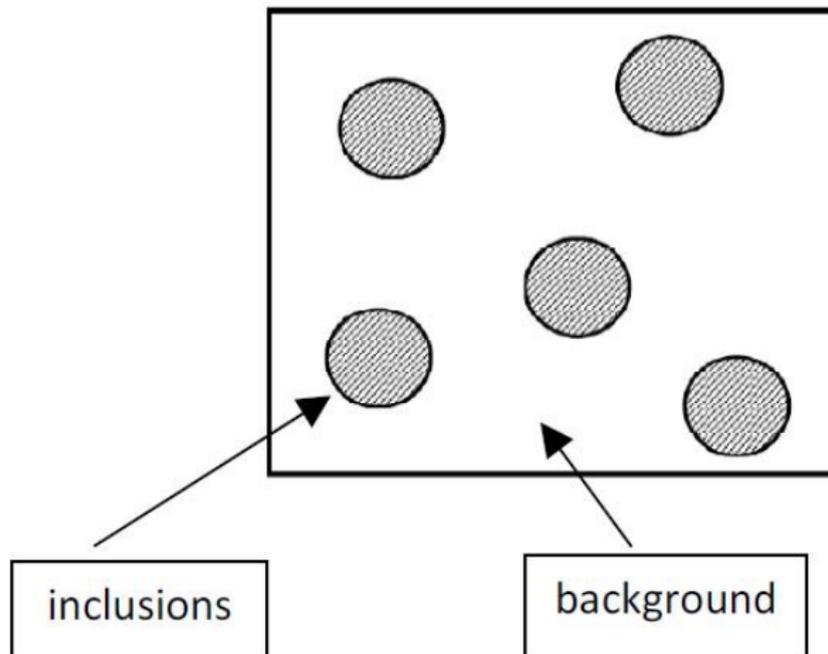
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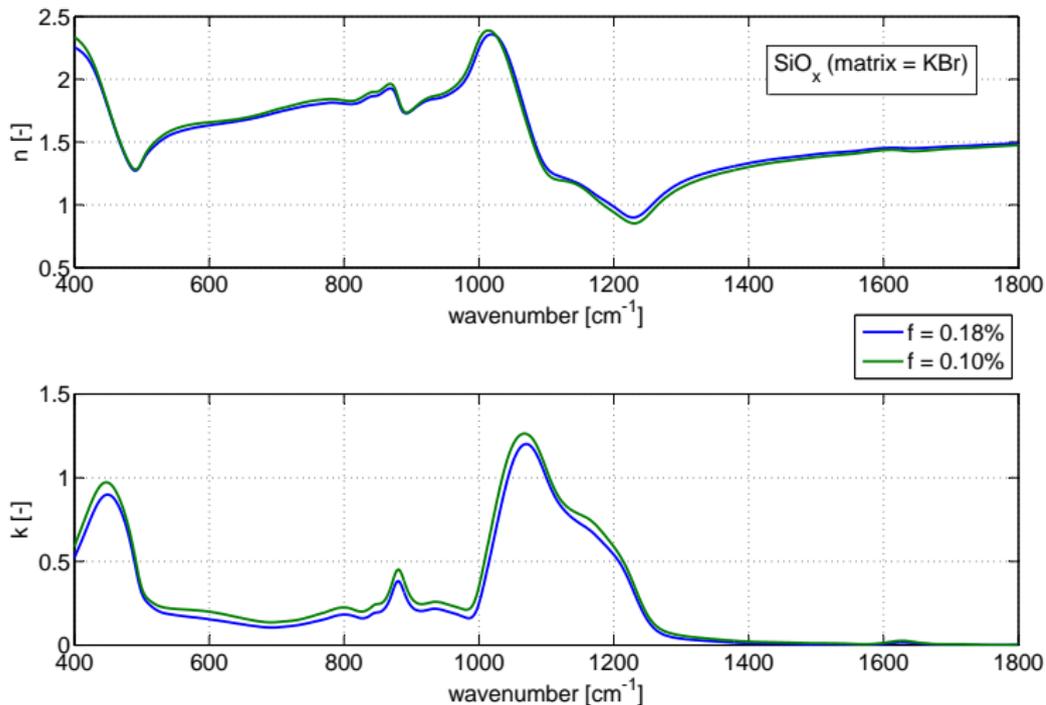
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Thanks!
Questions?

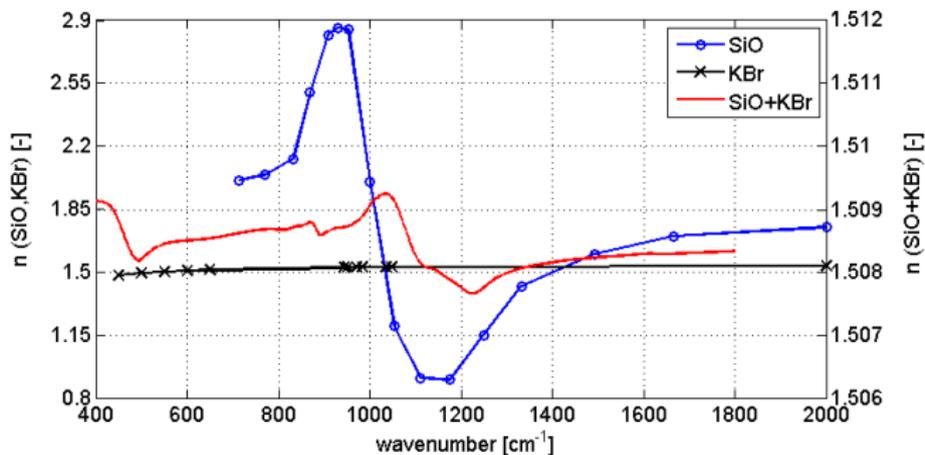
The effective medium structure

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The optical constants as a function of filling fraction

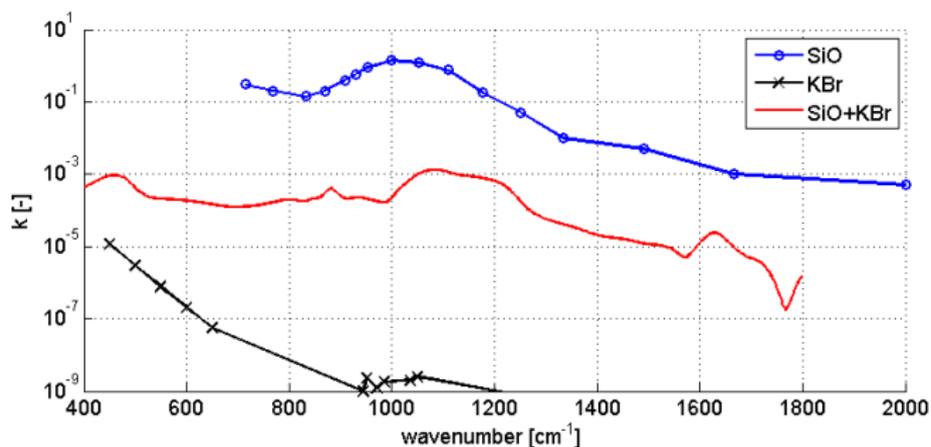
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The optical constants for the $\text{SiO}_x - \text{KBr}$ mixture

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